

**Notice of References Cited**

Application/Control No.

09/842,403

Applicant(s)/Patent Under  
Reexamination  
ITO ET AL.

Examiner

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Art Unit

2823

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**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6,407,009 b1	06-2002	You et al.	438/782
	B	US-5,925,410 a	07-1999	Akram et al.	427/240
	C	US-6,066,575 a	05-2000	Reardon et al.	438/782
	D	US-6,461,983 b1	10-2002	Davlin et al.	438/782
	E	US-6,423,380 b1	07-2002	Courtenay, Robert William	427/421
	F	US-2001/0029111 a1	10-2001	YOU et al.	438/782
	G	US-5,843,527 a	12-1998	Sanada, Masakazu	427/240
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	JP 62051221 A	03-1987	Japan	IMAMURA et al.	H01L 21/30
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

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